



Paper No. 4

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OFFICE OF PETITIONS

In re Application of :
Tamura, et al. :
Application No. 09/812,690 :
Filed: March 21, 2001 :
Attorney Docket No. 53375/1385 :

ON PETITION

This is a decision on the papers styled "Petition To Accord Filing Date (37 CFR 1.182)" filed on August 30, 2001, which is being treated as a petition under 37 CFR 1.53, requesting that the above-identified application be accorded a filing date of March 21, 2001, including seven (7) sheets of drawings.

The application was filed on March 21, 2001. However, on July 12, 2001, the Office of Initial Patent Examination (OIPE) mailed a "Notice Of Incomplete Nonprovisional Application" (Notice) that stated the application had not been accorded a filing date, and that the application was deposited without drawings.

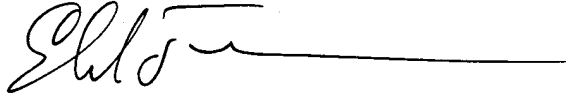
In response, on August 30, 2001, a petition with petition fee and seven (7) sheets of drawings were submitted. The papers were accompanied by a copy of applicant's postcard receipt that acknowledges receipt of eight (8) drawings on seven (7) sheets of drawings ("No. Of Drawings 8; No. Of Drawing Pages 7") on March 21, 2001. Drawings dated March 21, 2001 have not been found after review of the application file. It is assumed that the seven (7) sheets of drawings submitted on March 21, 2001 were misplaced by the Office.

In view of the above, the petition is granted.

The \$130.00 petition fee is not necessary and has not been charged.

This application will be returned to OIPE for further processing with a filing date of March 21, 2001, using the seven (7) sheets of drawings, supplied on August 30, 2001.

Telephone inquiries concerning this matter may be directed to Petitions Attorney Edward Tannouse at (703) 306-9200.



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